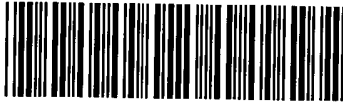


<b>Issue Classification</b> 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	09/943,690	WEIER ET AL.	
	Examiner	Art Unit	
	Tae H. Yoon	1714	

ISSUE CLASSIFICATION									
ORIGINAL				CROSS REFERENCE(S)					
CLASS		SUBCLASS		CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
524		504		524	819	823			
INTERNATIONAL CLASSIFICATION?				523	201	206			
C08L	5100	525	71						
C08L	33100								
	/								
	/								
	/								
(Assistant Examiner) (Date)				TAE H. YOON PRIMARY EXAMINER			Total Claims Allowed: 8		
(Legal Instruments Examiner) (Date)				Tae H. Yoon 11-13-04 (Primary Examiner) (Date)			O.G. Print Claim(s) 1		O.G. Print Fig. —

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant				<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
Final	Original	Final	Original	Final	Original	Final	Original	Final	Original
	1		31		61		121		181
2	2		32		62		122		182
	3		33		63		123		183
1	4		34		64		124		184
3	5		35		65		125		185
4	6		36		66		126		186
5	7		37		67		127		187
6	8		38		68		128		188
7	9		39		69		129		189
8	10		40		70		130		190
	11		41		71		131		191
	12		42		72		132		192
	13		43		73		133		193
	14		44		74		134		194
	15		45		75		135		195
	16		46		76		136		196
	17		47		77		137		197
	18		48		78		138		198
	19		49		79		139		199
	20		50		80		140		200
	21		51		81		141		201
	22		52		82		142		202
	23		53		83		143		203
	24		54		84		144		204
	25		55		85		145		205
	26		56		86		146		206
	27		57		87		147		207
	28		58		88		148		208
	29		59		89		149		209
	30		60		90		150		210